Power PUFs: Strengthening SRAM PUFs against Fault Injection on Low-Cost IoT Devices

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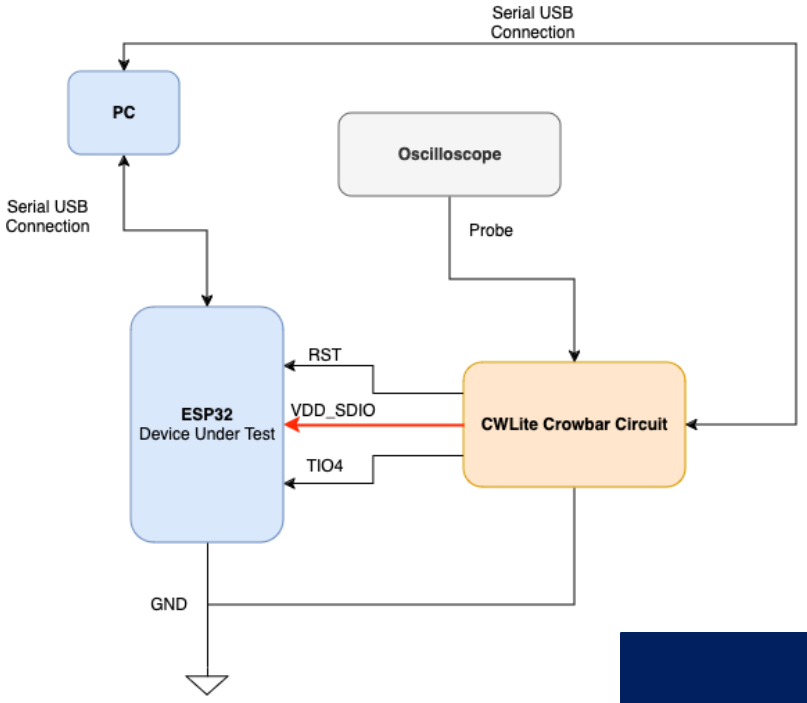
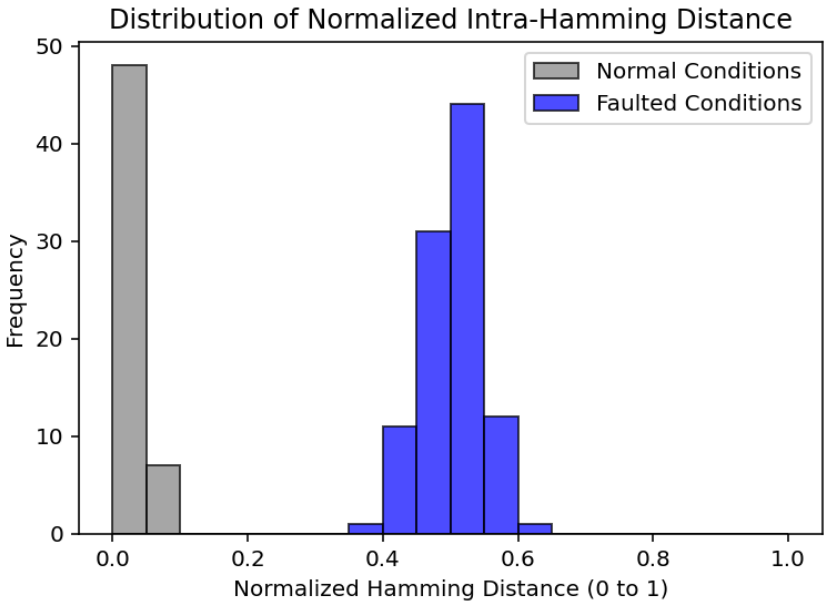


Research Question

How does intentional voltage glitching affect SRAM PUF behavior?



Results

Crowbar voltage glitching undermines the **PUF reliability metric** of ECC-encoded SRAM PUF IDs

Impact

Understanding vulnerabilities in PUFs can help make them more robust for high-reliability and security IoT applications

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